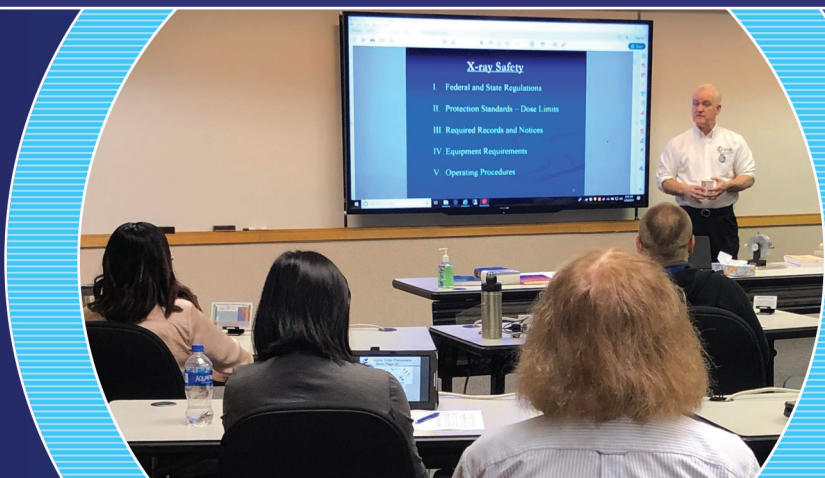




XRF

X-RAY FLUORESCENCE COURSES

Fundamentals of XRF I: 5 – 9 April 2027
Advanced Methods in XRF II: 12 – 16 April 2027

Techniques & Skills to Maximize Results!



FUNDAMENTALS COURSE OUTLINE

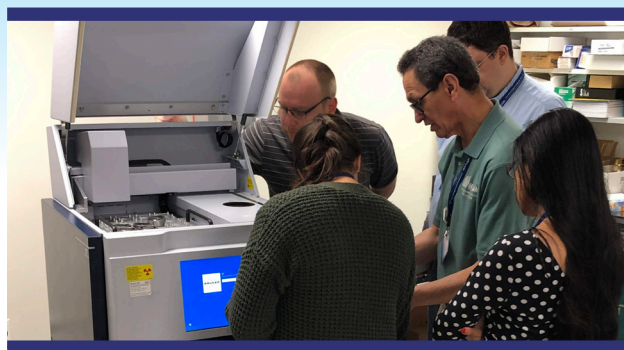
- Fundamentals of X-ray Physics
- WDX and EDX X-ray spectrometry instrumentation
- Qualitative, semi-quantitative, and standardless analysis
- Introduction to quantitative analysis
- Types and sources of error
- Precision and accuracy
- Calibration strategy
- Drift, line and interelement correction application
- Fundamental parameters
- Maintaining instrument integrity
- Specimen preparation



ADVANCED METHODS COURSE OUTLINE

- Recap of XRF Basics
- Method Development the way from start to finish
- Defining Scope, Detection, Quantification limits, and Tolerances
- Reference Materials
- Preparation selection and constraints
- WDX: Getting the “right” Net intensity: background correction, overlap correction, spectral contamination corrections; EDX deconvolution methods
- From Net intensity to Concentration: Overview of Matrix compensation/correction methods
- Internal standard methods and Compton Correction
- Fundamental parameters: the fluorescence process explained and calculated
- Influence coefficients: Empirical and theoretical approaches
- Borate Fusion: Making recipes - Flux selection; Dilution and mixing
- Calibration, validation, and drift correction

CUTTING-EDGE EQUIPMENT DEMONSTRATIONS



TXRF • HANDHELD XRF • FUSIONS

Please note: A minimum of 10 registrants per course is required, otherwise the course will be cancelled and your registration fee will be refunded. You will be notified of a course cancellation no later than two weeks prior to the start of the course.

See website for early registration deadlines.

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